

FUSE CIRCUIT FOR SEMICONDUCTOR INTEGRATED CIRCUIT

Abstract of the Disclosure

5 In a fuse circuit including programmable fuses in a semiconductor
 integrated circuit, the fuses store specific information related to the
 semiconductor integrated circuit, such as redundancy information, wafer lot
 number, die lot number, and die position on the wafer, etc. While a
 conventional semiconductor integrated circuit utilizes a single fuse for storing
 one bit of specific information, the fuse circuit in the present invention utilizes
 a plurality of fuses for storing identical bit information. Consequently, in the
 case where a fuse has not been cut out correctly, the fuse circuit of the present
 invention can reduce programming defects, whereby defect generation rates
 are remarkably decreased.

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